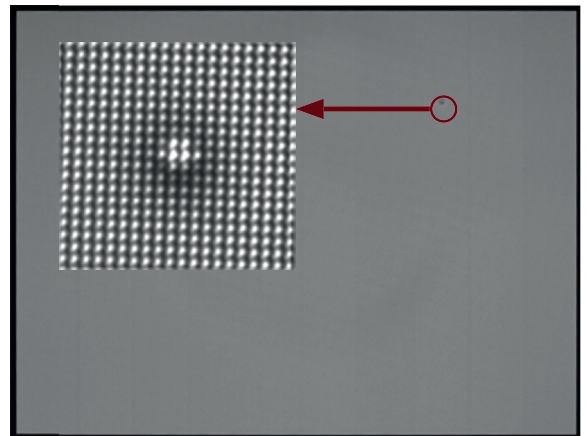
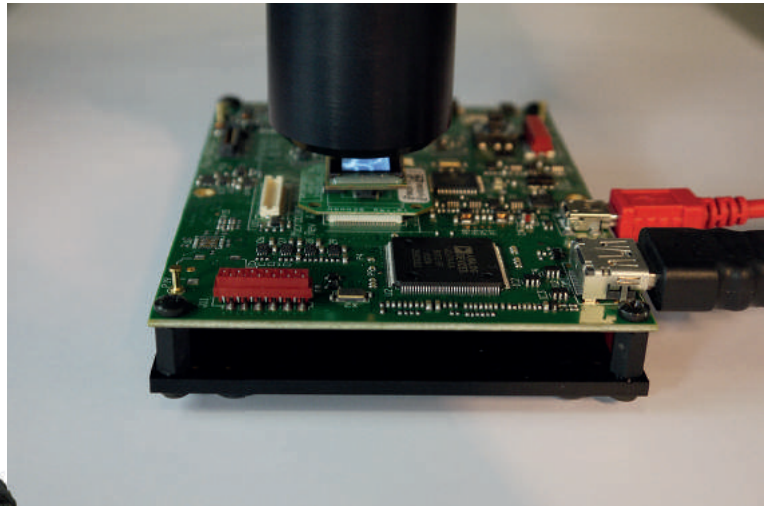


XSP-3



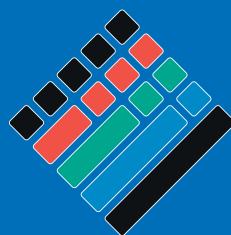
FEATURES

- High magnification and ultra-large field of view
- Spatial resolution of $1.5\mu\text{m}$
- Automatic focus and tilt correction
- gSOAP toolkit, innovative multi-OS software development platform

APPLICATIONS

- Microdisplays inspection
- Detailed pixel sub-structure studies
- LEDs die inspection
- Any photometry application down to the micrometer scale

ELDIM XSP line solutions are high field analyzers ideally suited for small and micro displays. In addition to an ultra large field of view and high spatial resolution video colorimeter, 3 automated axes provide autofocus and tilt correction, a successful match to obtain a complete quality evaluation system with fast scan speed and accurate imaging data.



ELDIM

OPTICAL METROLOGY FOR DISPLAYS

Specifications	XSP-3	XSP-4
Spatial resolution	1.5µm	1.5µm
Magnification	4.5	4.5
FOV	10.9x8.2mm	10.9x8.2mm
Sensor	50 Mpix	50 Mpix
High speed sensor	Yes	Yes
Measurement**	<2s / pattern	<5mn / pattern
Spectral technology	Spectrometer	Bandpass filters
Spectral resolution	2nm	5nm
Luminance by pixel	No	Yes
Spectrum by pixel	No	Yes
Spectrum by display	Yes	Yes
Autofocus	Yes	Yes
Automatic tilt correction	Yes	Yes
X automated	Yes	Yes
X range	300mm	300mm
Y automated	No	Yes
Y range	Fixed	100mm
Z automated	Manual	Yes
Z range	50mm	50mm
Sample holder	Option	Option
Frame grabber	Yes	Yes
Data format	XML	XML
Programming	SOAP based	SOAP based
Operating system	OIS, Windows, Linux, UNIX	OIS, Windows, Linux, UNIX
Analysis	SDK provided	SDK provided
Height	1100mm	1100mm
Width	520mm	520mm

XSP Outer dimension (unit mm)

